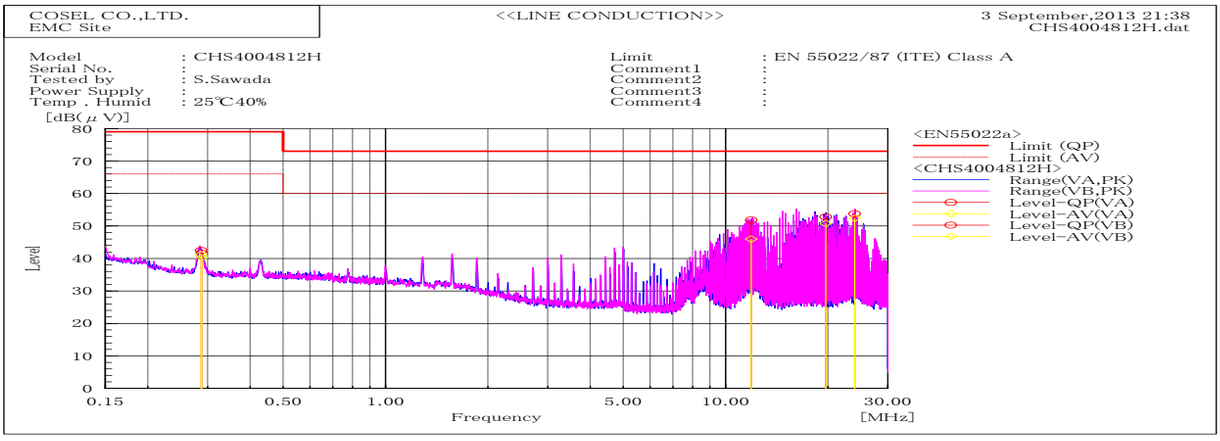
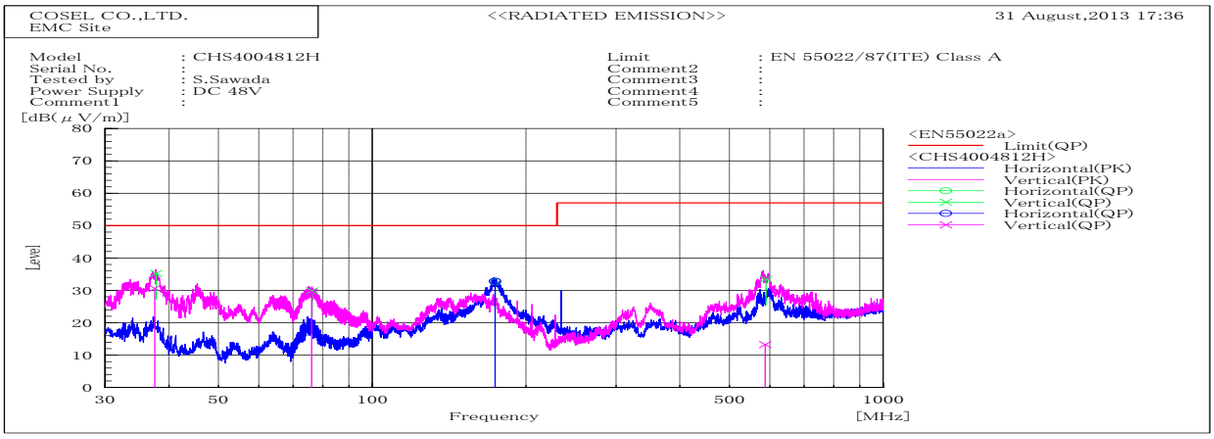
参考資料

COSEL

DATA SHEET		Date	03-Sep-13
Model	CHS4004812H	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Sawada



Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.28726		VA	21.5	20.1	20.1	41.6	40.2	79	66	37.4	25.8	Pass	
0.28814		VB	22.4	21.1	20.1	42.5	41.2	79	66	36.5	24.8	Pass	
11.9008		VA	31.1	25.3	20.7	51.8	46	73	60	21.2	14	Pass	
19.7062		VB	31.8	29.7	21	52.8	50.7	73	60	20.2	9.3	Pass	
23.9763		VA	32.8	31.4	21	53.8	52.4	73	60	19.2	7.6	Pass	

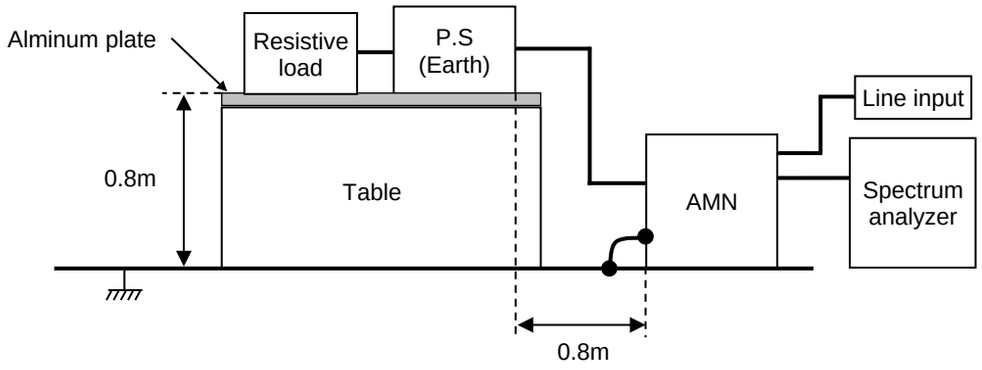


Frequency MHz	Polarization	Stability	Reading dB(uV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP		QP	QP	QP				
37.51	V	Stable	47.8	-17.2	30.6	50	19.4	Pass	100	77	
76.118	V	Stable	54.6	-25.1	29.5	50	20.5	Pass	100	127	
173.899	H	Stable	55	-22.2	32.8	50	17.2	Pass	101	16	
587.207	V	Stable	23.6	-10.3	13.3	57	43.7	Pass	160	210	

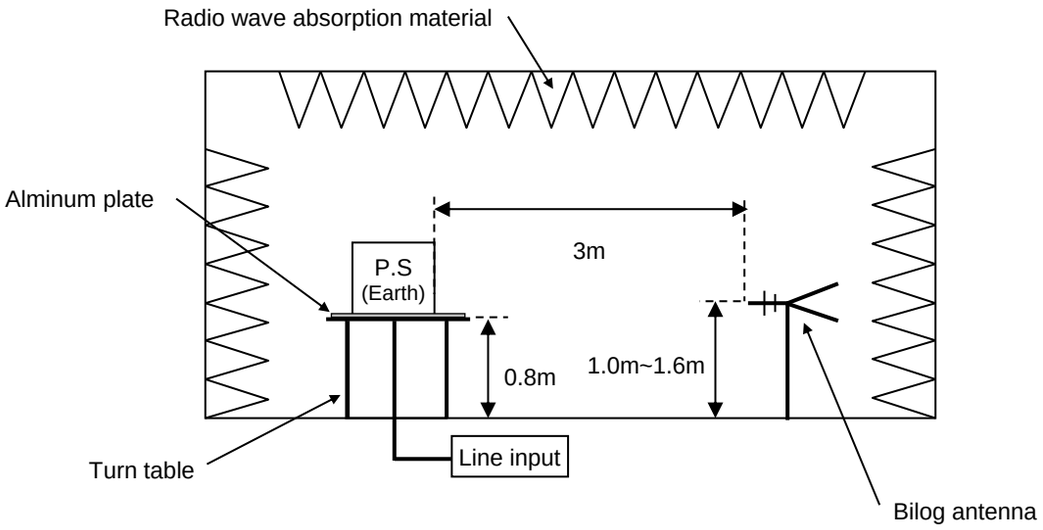
COSEL

DATA SHEET		Date	03-Sep-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Sawada

1. Line conduction



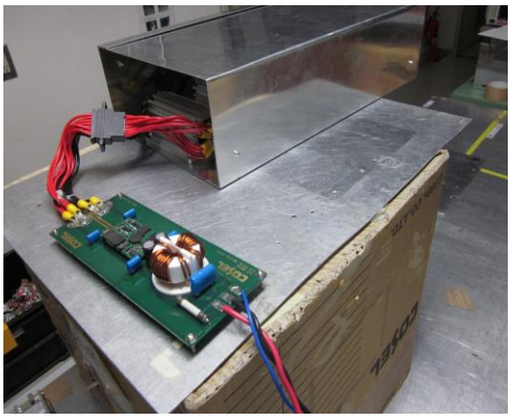
2. Radiated emission



Test: EMI
Model Name:CHS40048□

○ Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION

○ Testing circuitry

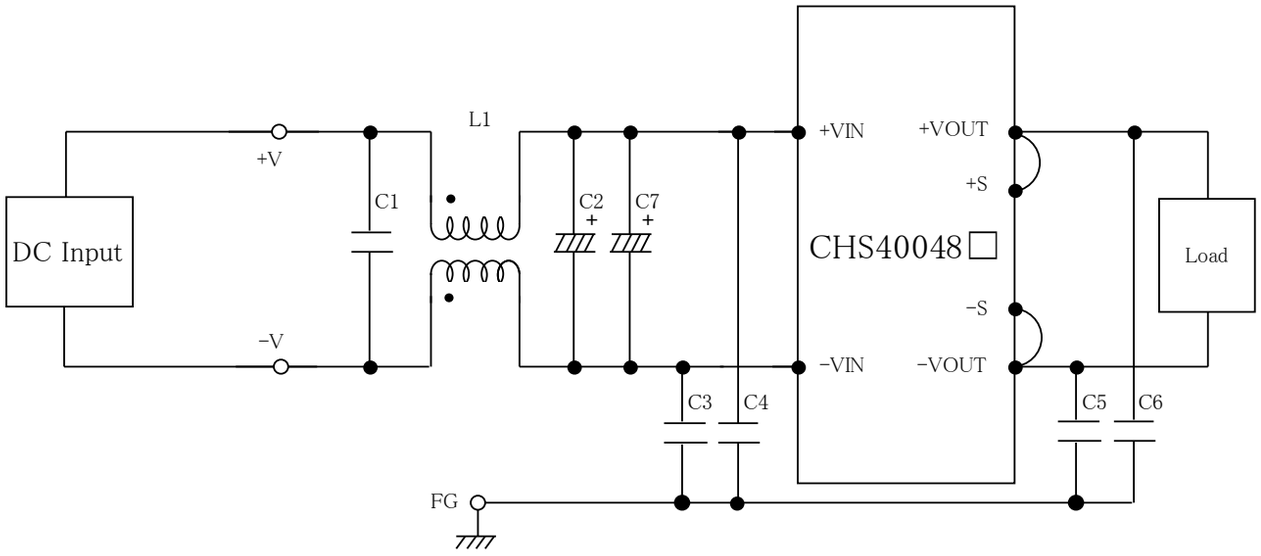


Fig.1 Testing circuitry

L1 : 1mH SC-20-10JH (TOKIN)
C1 : 250V 2.2μF FPD22E225J4 (NITSUKO)
C2,C7 : 100V 100μF PWseries (nichicon)
C3,C4 : 630V 0.068μF FPD22J683J4 (NITSUKO)
C5,C6 : 630V 0.033μF FPD22J333J4 (NITSUKO)